



#614
00
11/6/02

Docket No.: M4065.0424/P424
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
William E. Corr

Application No.: 09/808,140

Group Art Unit: 2858

Filed: March 15, 2001

Examiner: Not Known

For: CIRCUIT FOR MEASURING ON-CHIP
POWER SUPPLY INTEGRITY

RECEIVED
OCT 30 2002
TC-2800 MAIL ROOM

PRELIMINARY AMENDMENT

Commissioner for Patents
Washington, DC 20231

RECEIVED

NOV 04 2002

Dear Sir:

Technology Center 2100

Prior to examination, please amend the above-captioned application as follows:

In the Claims:

✓
Cancel claims 2, 34, 48, 54 and 77, without prejudice.

↙
Replace 1, 3, 6, 8-11, 24-27, 31-33, 35, 38-41, 45-47, 49, 51, 53, 55, 58, 60-63, 76, 78, 81 and 83-86 with amended claims 1, 3, 6, 8-11, 24-27, 31-33, 35, 38-41, 45-47, 49, 51, 53, 55, 58, 60-63, 76, 78, 81 and 83-86 below.

1. (Amended) A method for measuring a parameter of a circuit under test, the method comprising:

- A1
- (a) charging a first portion of a test circuit up to a first voltage level;
 - (b) charging a second portion of said test circuit up to a second voltage level;